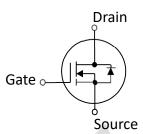


## 30V N-Channel MOSFET

- Advanced Split Gate Device Design and Processes
- High Reliability Capability
- Sampled CP Probing





Electrica	al Characteristics in C/P Test	t (TJ a	ıt 25 °	C)		
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	30		_	٧	$V_{GS} = 0V, I_D = 250 \mu A$
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	5.3	6.7	mΩ	$V_{GS} = 10V, I_D = 1A(1)$
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	6.1	7.7	mΩ	$V_{GS} = 4.5V, I_D = 1A(1)$
V <sub>GS (th)</sub>	Gate Threshold Voltage	1	_	3	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA
I <sub>DSS</sub>	Drain-to-Source Leakage Current		7	1	μA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V
I <sub>GSS</sub>	Gate-to-Source Leakage Current	-100	_	100	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature			-55	5°C to 1	50°C Max.

Mechanical Data		Die Drawing
Chip Size <sup>(2)</sup>	1433 µm X 896 µm	896 um
Gate Pad Size	180 µm X 180 µm	
Source Pad Size	823 X 636 μm	
Scribe Line Width	60 µm	823.55 um
Wafer Thickness	100 μm	
Wafer Diameter	200 mm	636.475 um
Gross Die	20239 EA	433.55 ur
Source Metallization	Ni 2-4um / Pd 2k-3kA / Au 200-500A	
Drain Metallization	Ti-Ni-Ag	180um
Passivation	Polyimide	
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C	

<sup>(1)</sup> Pulse Width tp = < 1 mS, Duty Cycle < 2%.

<sup>(2)</sup> Chip size not include scribe line.

## SPQ6R7N30WPI

Specific Assembly Info	rmation Bill of Material (BOM)	Die Drawing
Package Type	DFN5*6	896 um
Die Attach Method	Soft solder	823.55
Soft Solder Composition	Pb,Sn,Ag	55 um
Gate Wire Bonding	Cu, 2 mil x1	636.475 um  1433.55
Source Wire Bonding	Cu clip	
Molding Compound Manufacturer	G700HF	180um 1
Solder Plating Composition	Pure Tin	

	Pos	ition	Bonding Diagram Top View		
	X (μm)	Y (μm)	ZERO		
ZERO	0	0	51		
ТОР	1433.55	896.475			
S1	130	130	52		
S2	953.55	766.475	2		
G1	1203	51.7	G1 G2		
G2	1383	231.4	10Р		



## SPQ6R7N30WPI

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I <sub>DSS</sub>	Drain-to-Source Leakage Current	_	_	1	μΑ	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V
I <sub>GSSF</sub>	Gate-to-Source Leakage Current	_	_	100	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =+20V
I <sub>GSSR</sub>	Gate-to-Source Leakage Current	_	_	-100	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =-20V
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	30	_	_	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	30	_	_	V	V <sub>GS</sub> =0V, I <sub>D</sub> =1mA
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	_	7.5	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =12A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	_	12	mΩ	V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A
V <sub>GS (th)</sub>	Gate Threshold Voltage	1	_	3	٧	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
V <sub>SD</sub>	Body Diode Forward Voltage	_	_	1.2	V	V <sub>GS</sub> =0V, I <sub>SD</sub> =12A
I <sub>AS</sub>	Avalanche Current				А	$V_{DD}$ =30V, $V_{GS}$ =10V, $R_{G}$ =25 $\Omega$ , L=0.5mH
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55		150	°C	

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